

FIG. 1

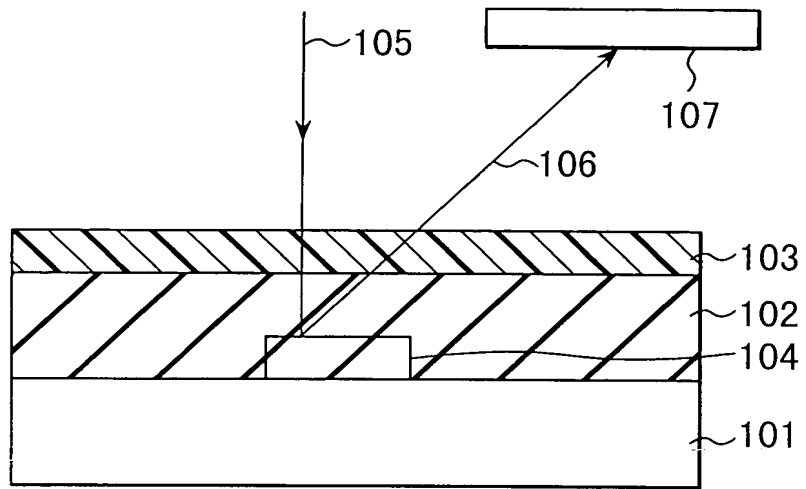


FIG. 3A

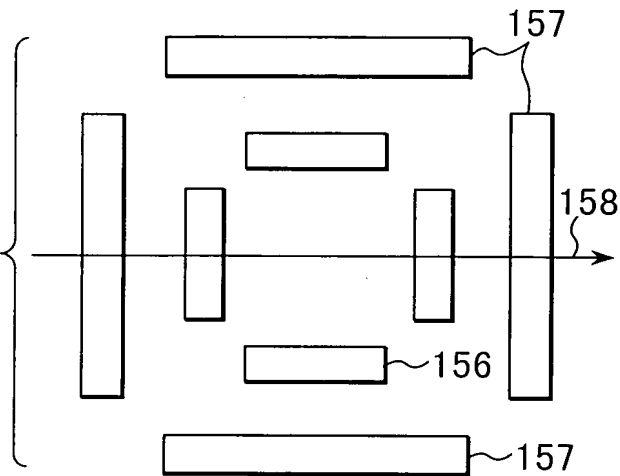
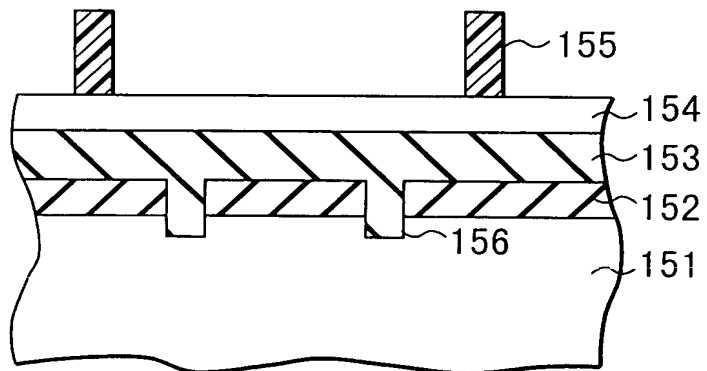


FIG. 3B



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FIG. 2A

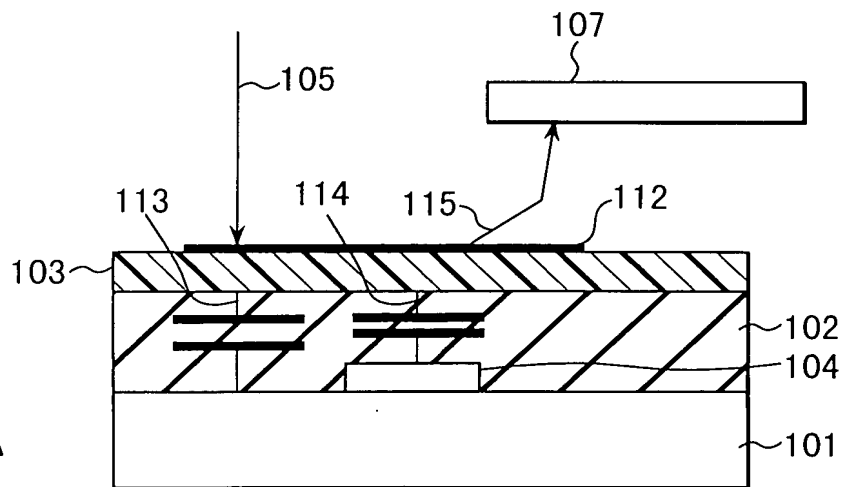


FIG. 2B

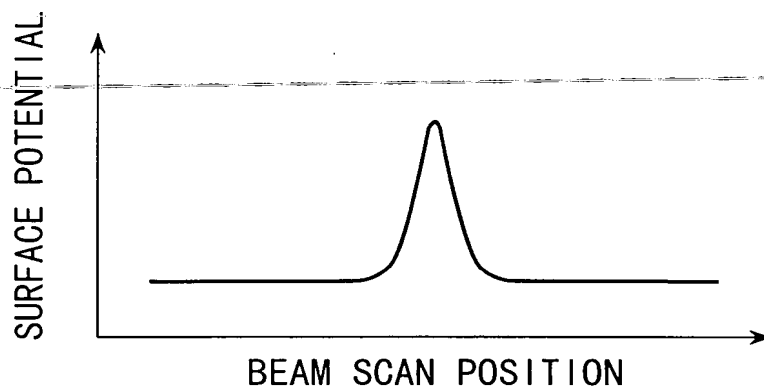


FIG. 2C

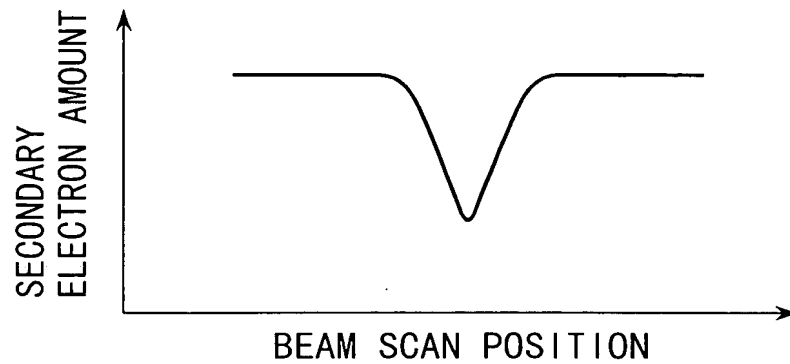


FIG. 2D

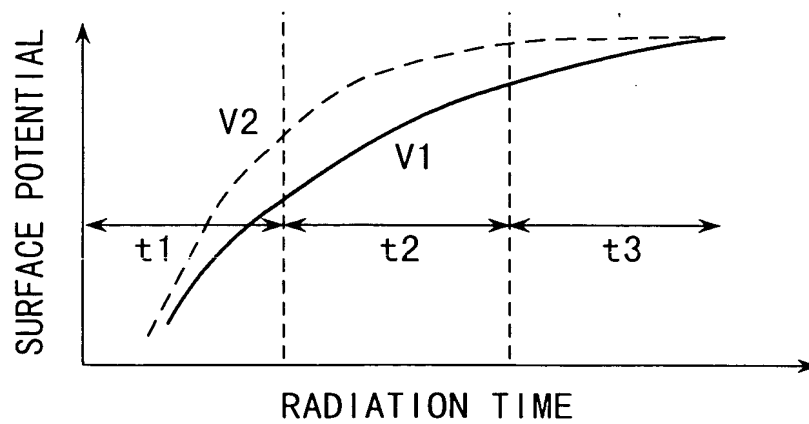


FIG. 4A

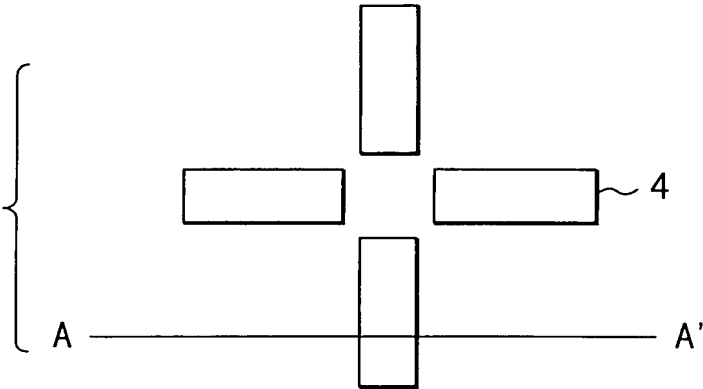
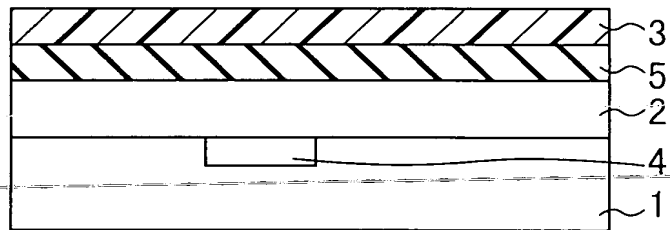


FIG. 4B



SHIFT MARK INTO DEFLECTION AREA

S1

SET FIRST RADIATION CONDITIONS

S2

FIRST BEAM EXPOSURE

S3

SET SECOND RADIATION CONDITIONS

S4

SECOND BEAM EXPOSURE

S5

ACQUIRE MARK IMAGE

S6

DETECT MARK POSITION

S7

DETERMINE PATTERN POSITION

S8

EXPOSURE

S9

FIG. 5

009260" 2E269960

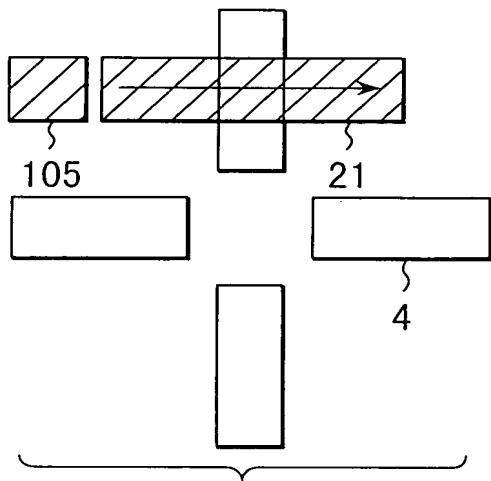


FIG. 6A

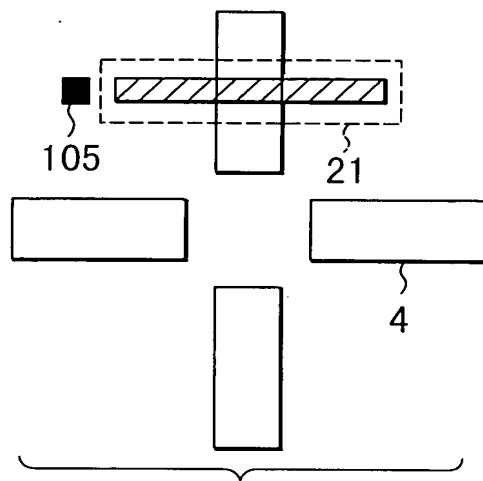


FIG. 6B

FIG. 7

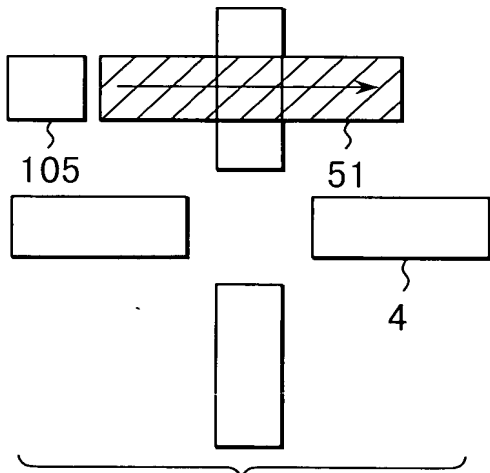
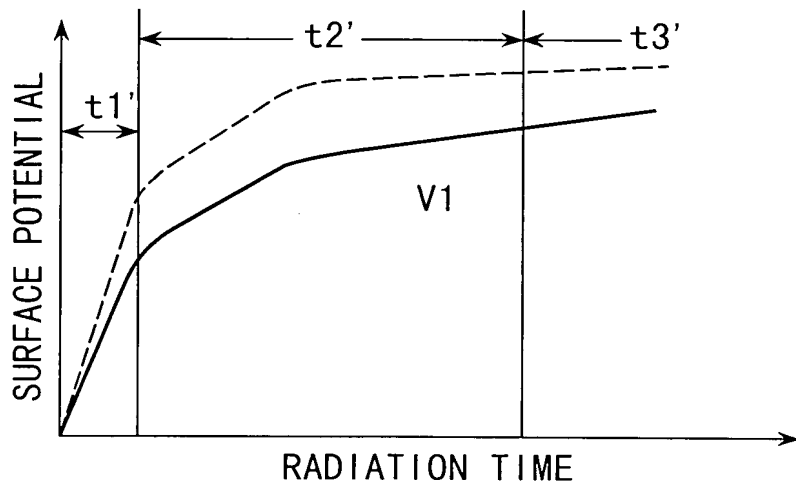


FIG. 8A

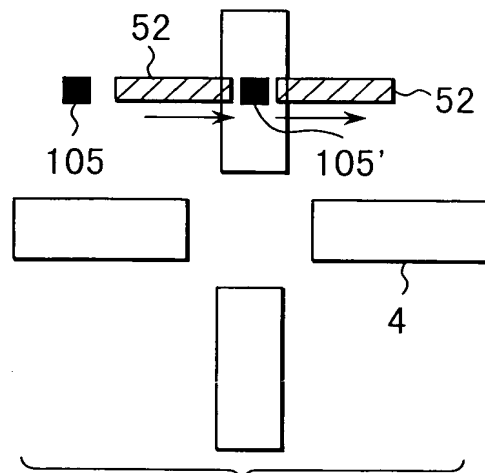
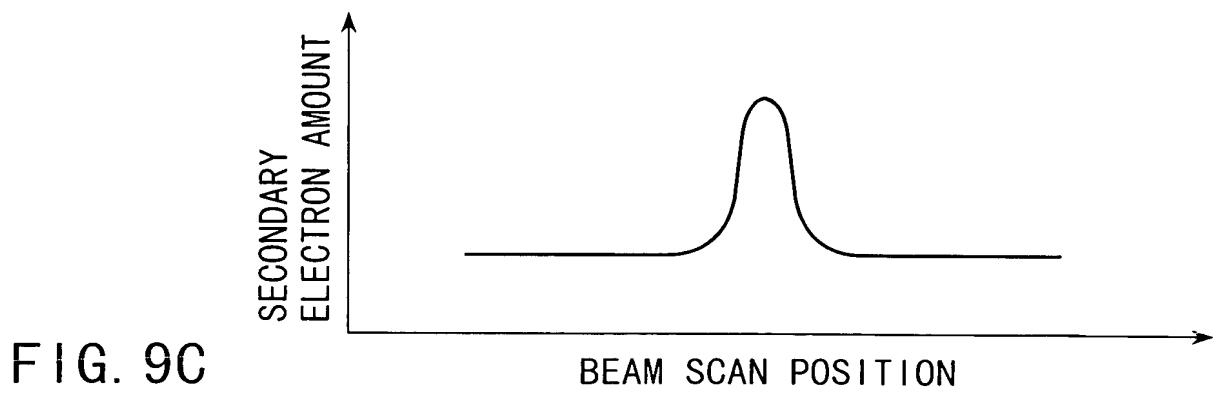
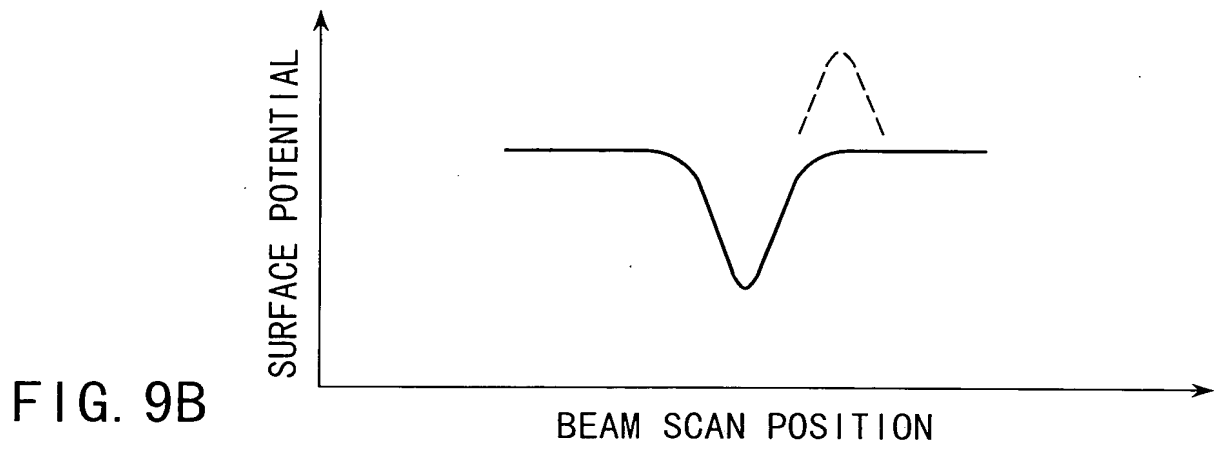
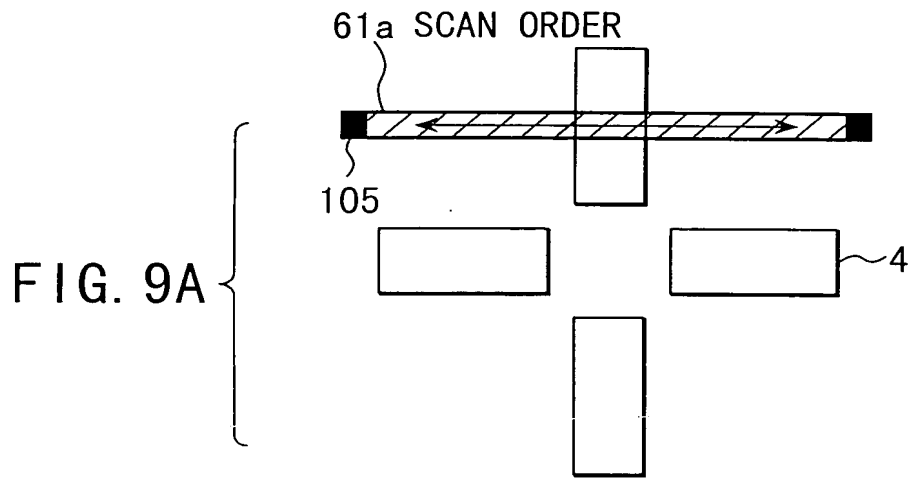


FIG. 8B

009260 25269960



009260 2E269960

FIG. 10A

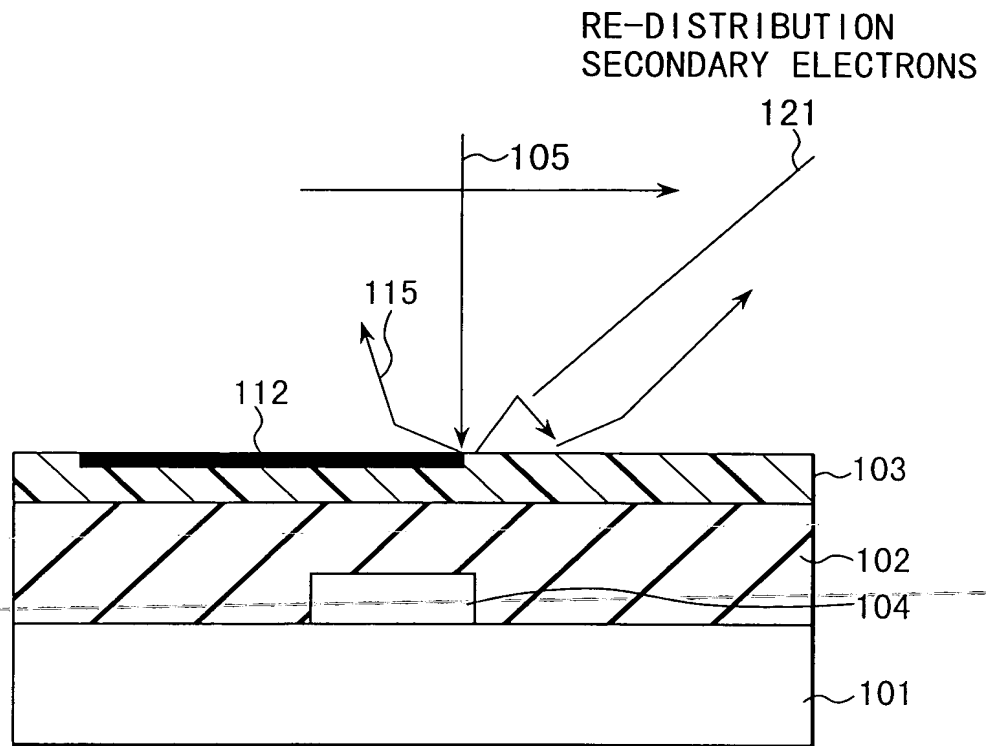


FIG. 10B

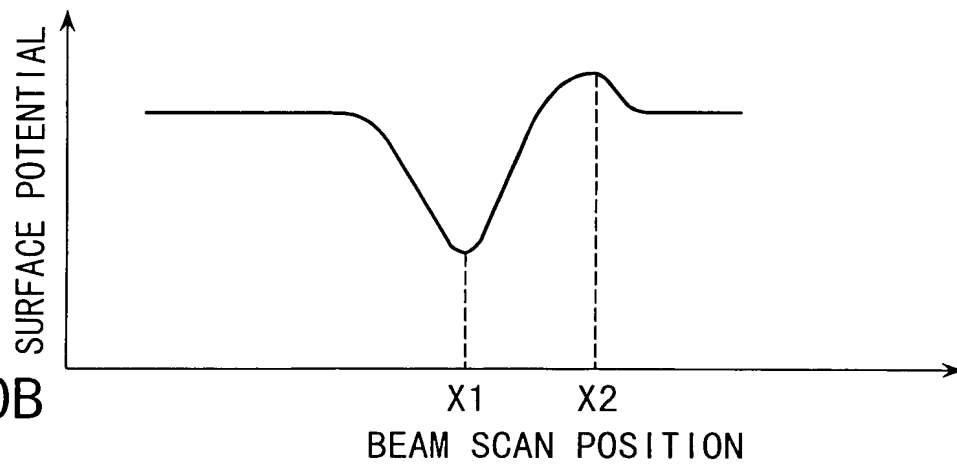
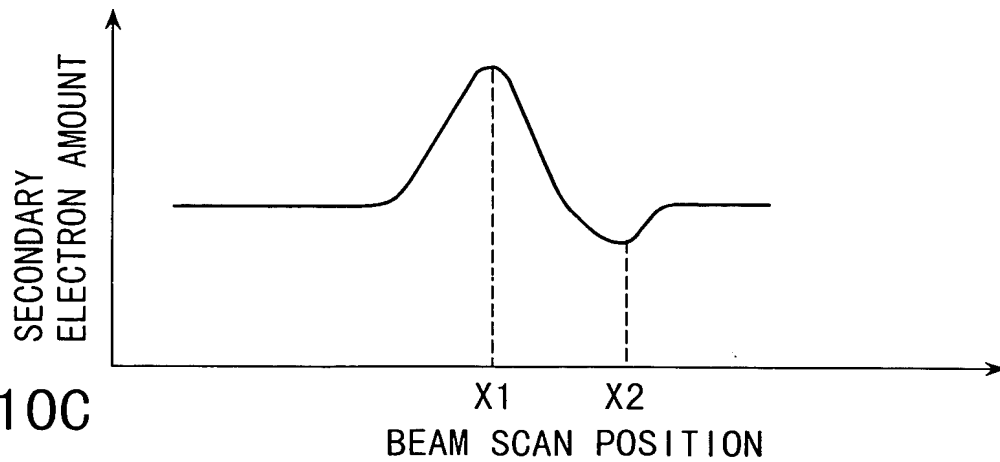


FIG. 10C



009260" 2E269960

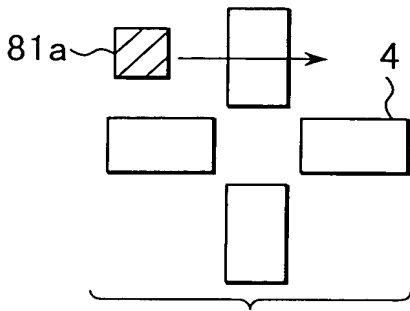


FIG. 11A

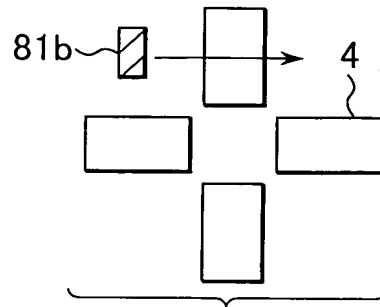


FIG. 11B

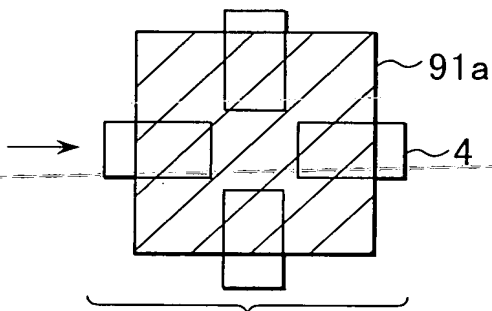


FIG. 12A

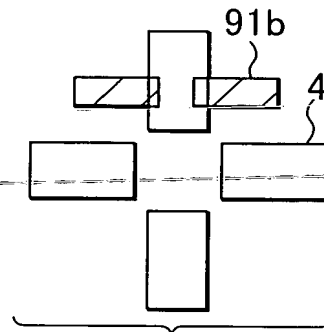
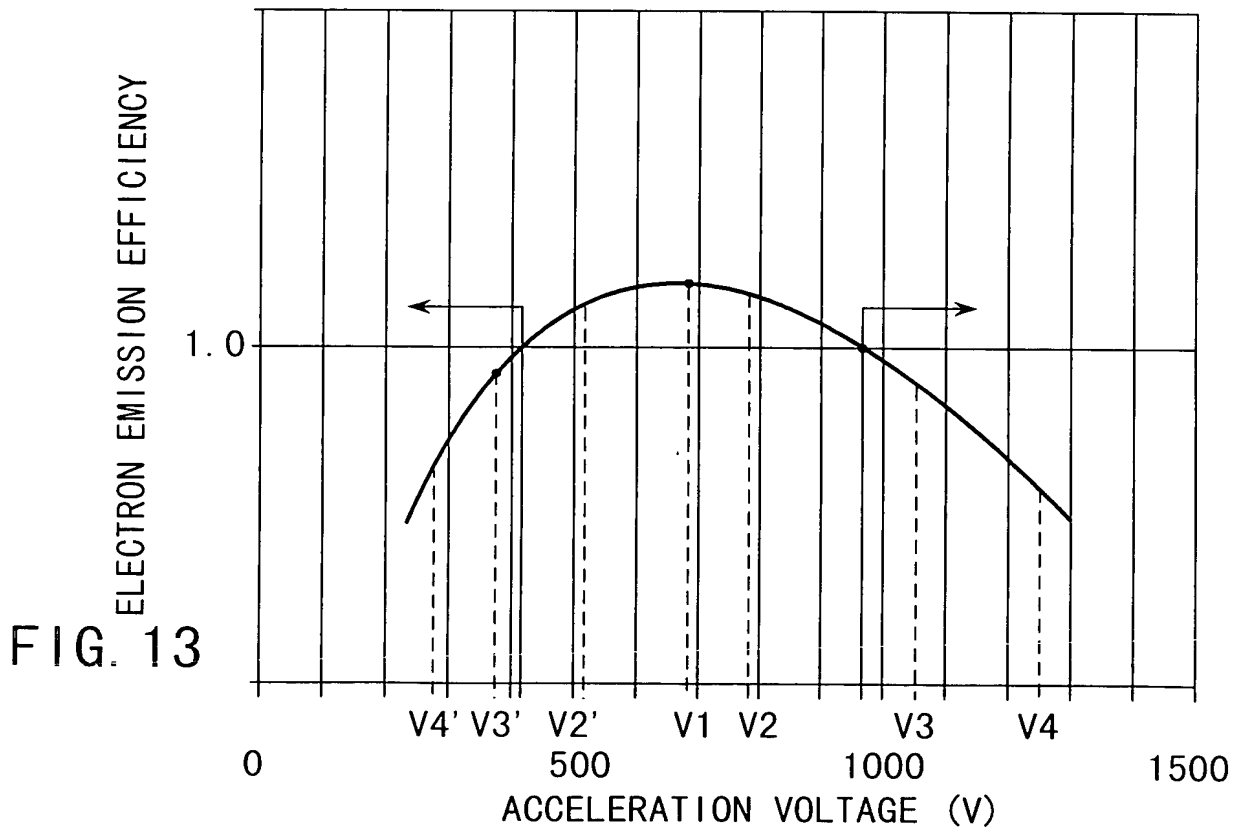


FIG. 12B



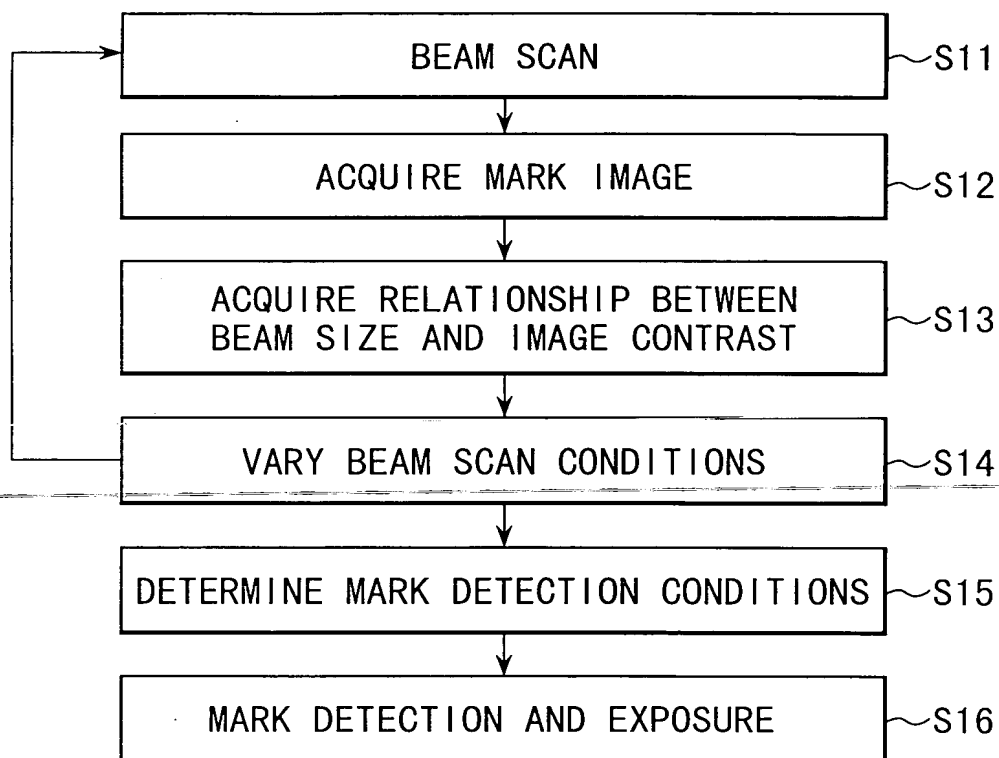


FIG. 14

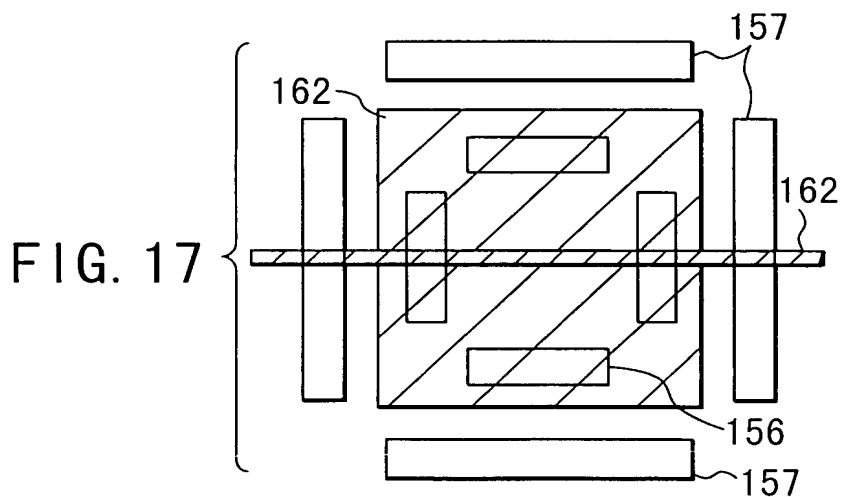


FIG. 17



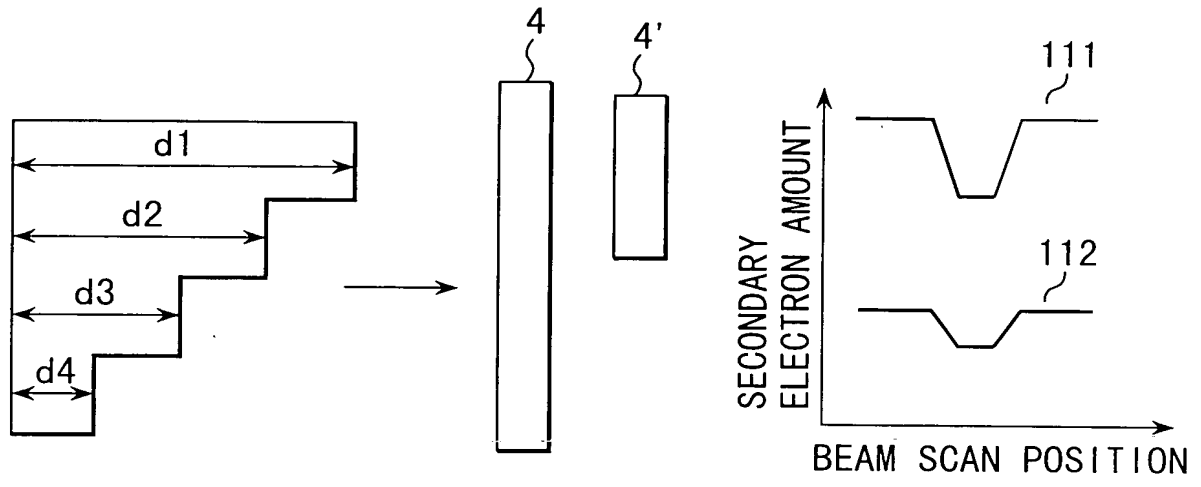


FIG. 15A

FIG. 15B

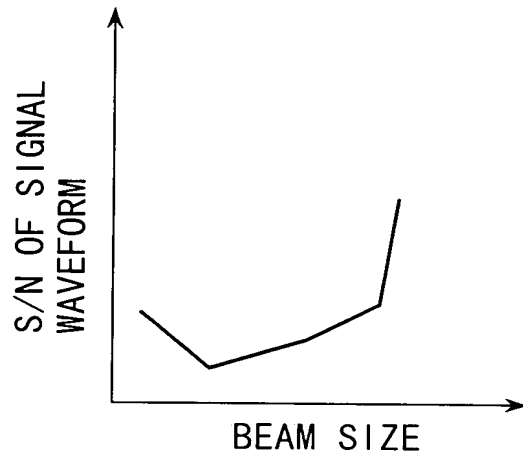


FIG. 15C

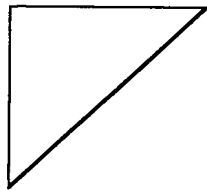
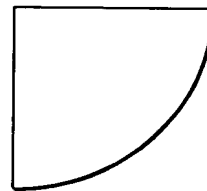
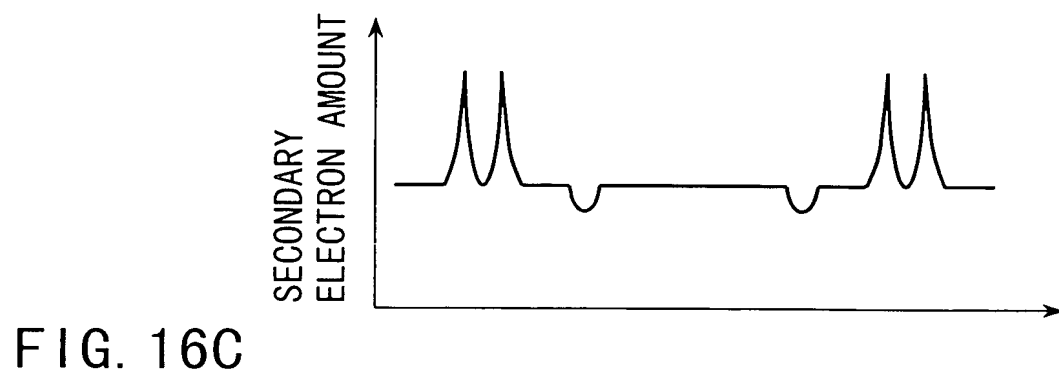
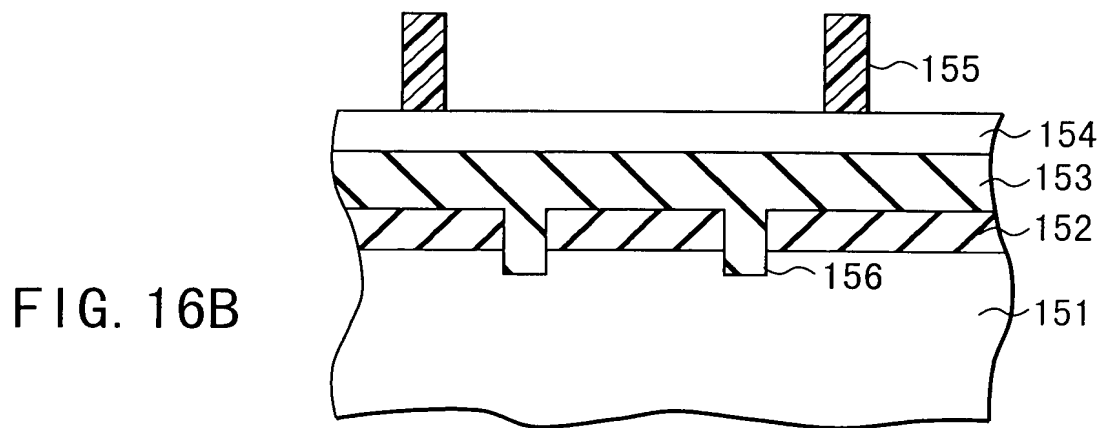
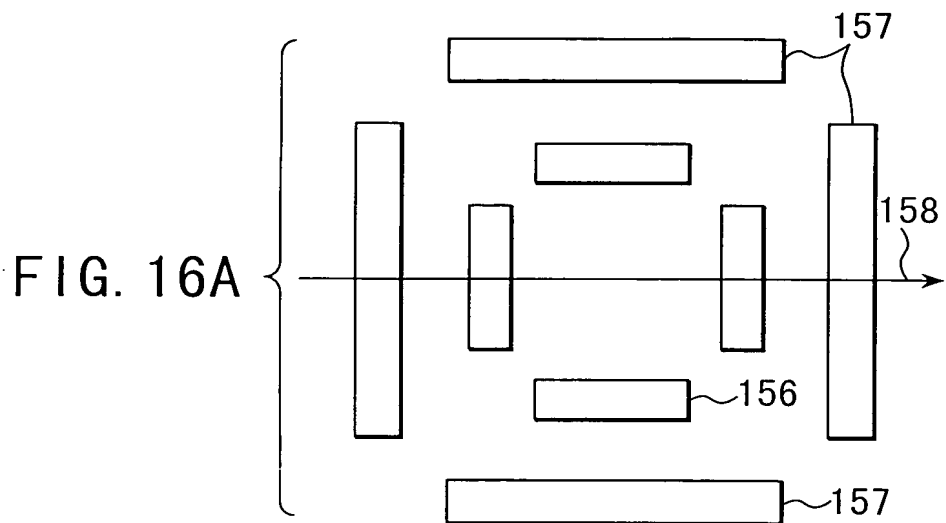


FIG. 15D



009260 2E269960



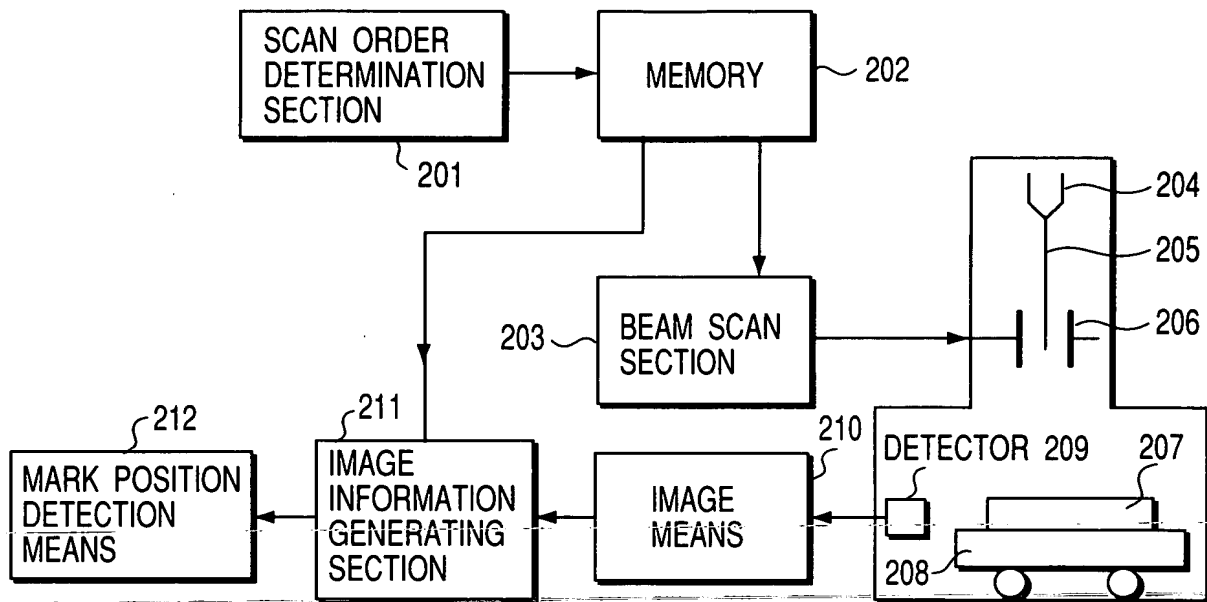


FIG. 18A

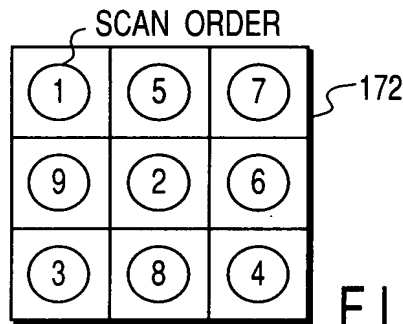


FIG. 18B

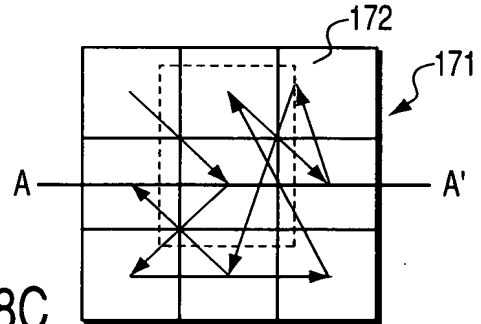


FIG. 18C

SCAN AREA

FIG. 18D

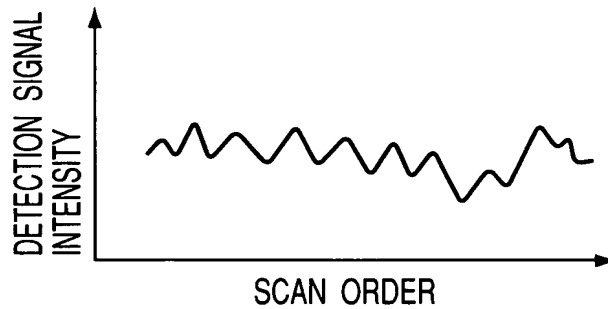


FIG. 18E

